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Baseline Proposal for 200G/L High Loss C2M

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IEEE P802.3dj Task Force

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Outline

- **Background and Introduction**
- **COM Link Budget Analysis for 200G/L High Loss C2M**
- **Main Challenges Facing 200G/L High Loss C2M**
- **Summary and Proposal**

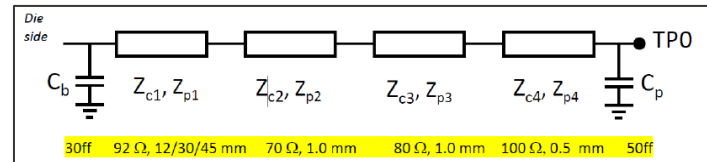
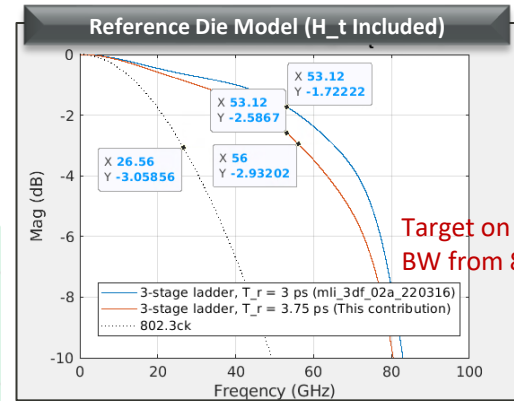
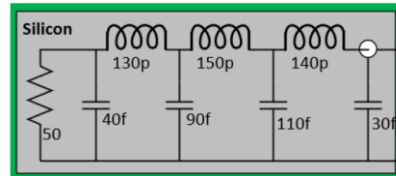
Background and Introduction

- Update to [tli_3df_01b_220316](#) “COM Simulation and Analysis for 200Gbps/Lane Chip-to-Module ” with
 - Updated device model based on [mli_3df_02a_220316](#) & [artsi_3df_01a_2211](#)
 - More posted channels from 802.3df and OIF
 - Target on 200Gbps/L high loss C2M
 - Updated COM reference TX & RX, which are the evolution from 802.3ck CR
- This presentation provide the direction for high loss C2M specification
 - Based extensively on [ran_3df_elec_01b_220921](#) and [lusted_3df_02_2211](#) with more COM simulations to construct a complete **baseline proposal**
 - Analyze feasibility of target loss and operating DER
 - Analyze equalization solutions to pass COM
- The intention of this presentation is NOT to
 - Address specific type of chip-to-module interface
 - Address specific ASIC implementation
 - Address specific compliance methodology

COM Simulation Setting

- Test methodology in this presentation: die-die evaluation for link budget analysis
- 112 test channels, details in [appendix](#)
- COM v3.90 adopted, COM spreadsheet in [appendix](#)
- Reference device model
 - Die model: [mli_3df_02a_220316](#) except $T_r = 3.75$ ps
 - Package model: [artsi_3df_01a_2211](#)

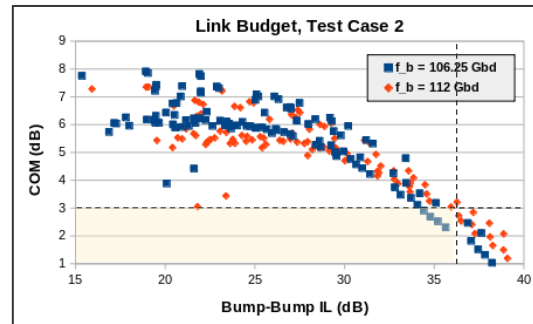
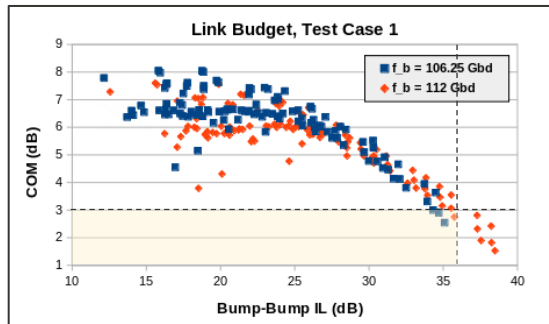
Parameter	Setting
C_d	[0.4e-4 0.9e-4 1.1e-4 ; 0.4e-4 0.9e-4 1.1e-4]
L_s	[0.13 0.15 0.14 ; 0.13 0.15 0.14]
C_b	[0.3e-4 0.3e-4]
T_r	3.75E-03
z_p (TX)	[15 30 ; 1 1 ; 1 1 ; 0.5 0.5]
z_p (NEXT)	[8 ; 0 0 ; 0 0 ; 0 0]
z_p (FEXT)	[15 30 ; 1 1 ; 1 1 ; 0.5 0.5]
z_p (RX)	[8 ; 0 0 ; 0 0 ; 0 0]
C_p	[0.5e-4 0.5e-4]
package_tl_gamma0_a1_a2	[0 0.0008455 0.000340225]
package_tl_tau	0.00644805
package_Z_c	[92 92 ; 70 70 ; 80 80 ; 100 100]



Baseline Evaluation for 200G/L High Loss C2M

- Key features of high loss C2M
 - Nominal signaling rate: 106.25 GbD
 - Modulation: PAM4 signaling
 - Operating BER: 1E-4
 - Target bump-bump IL: ~36 dB
 - COM reference TX & RX are an evolution from 802.3ck CR, scaled to the higher signaling rate

Parameter	802.3ck CR	802.3ck KR	This Presentation
DER_0	1.00E-04		
T_r	7.5 ps	7.5 ps	3.75 ps
SNR_TX	32.5	33	33
R_LM	0.95		
c(-1)	[-0.34:0.02:0]	[-0.34:0.02:0]	[-0.34:0.02:0]
c(-2)	[0:.02:0.12]	[0:.02:0.12]	[0:.02:0.12]
c(-3)	[-0.06:.02:0]	[-0.06:.02:0]	[-0.06:.02:0]
c(-4)	-	-	[0:.02:0.06]
c(1)	[-0.2:0.02:0]	[-0.2:0.02:0]	[-0.12:0.02:0.1]
sigma_RJ	0.01 UI		
A_DD	0.02 UI		
eta_0	9E-09	8.2E-09	4.1E-09
N_b	12	12	24
N_bg	3	3	6
N_bf	3	3	3
N_f	40	40	80

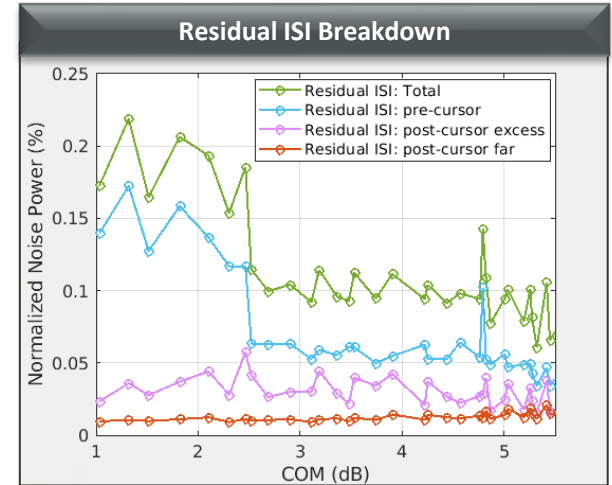
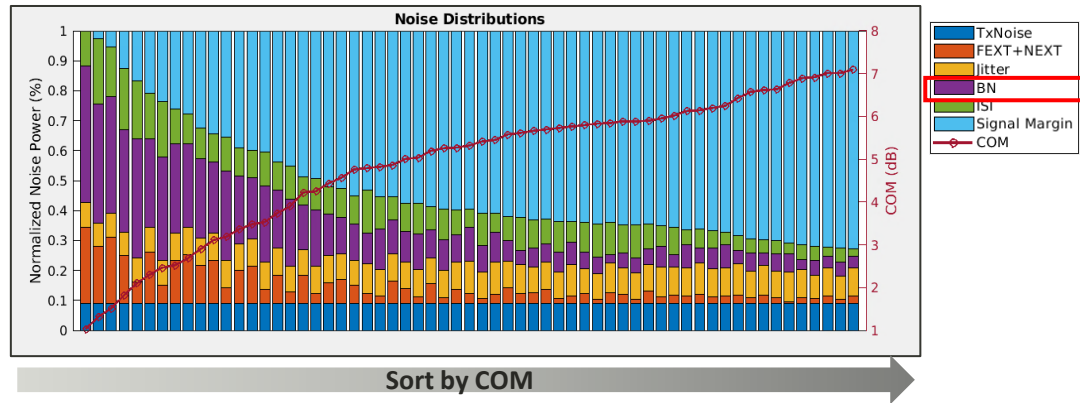


z_p select	[1 2]		(test cases to run)
z_p (TX)	[15 30; 1 1; 1 1; 0.5 0.5]	mm	(test cases)
z_p (NEXT)	[8 8; 0 0; 0 0; 0 0]	mm	(test cases)
z_p (FEXT)	[15 30; 1 1; 1 1; 0.5 0.5]	mm	(test cases)
z_p (RX)	[8 8; 0 0; 0 0; 0 0]	mm	(test cases)

Most of the channels with bump-bump IL <= 36dB can be guaranteed of 3 dB COM

Main Challenge of 200G/L High Loss C2M: Noise Enhancement

- Noise distribution defined in 93A.1.6



*Take test case 2 under baud-rate of 106.25GBd as example

* Choose channels with bump-bump IL ≥ 25 dB

- Noise enhancement majorly impacts the link performance
- TxFIR is reluctant to mitigate pre-cursor due to signal swing reduction, especially for higher loss channels

Summary and Proposal

- **Main challenge affect the feasibility of 200G/L high loss C2M**
 - Noise enhancement
 - Residual pre-cursor ISI
- **Baseline proposal for 200G/L high loss C2M**
 - Operating BER: 1E-4
 - Target bump-bump IL: ~36 dB
 - COM reference TX & RX are an evolution from 802.3ck CR

Parameter	802.3ck CR	802.3ck KR	Proposed Value for 200G/L High Loss C2M
DER_0	1.00E-04	1.00E-04	1.00E-04
SNR_TX	32.5	33	33
R_LM	0.95	0.95	0.95
TxFIR Length	5 (3 pre)	5 (3 pre)	6 (4 pre)
eta_0	9E-09	8.2E-09	4.1E-09
N_b	12	12	24
N_bg	3	3	6
N_bf	3	3	3
N_f	40	40	80

Appendix

COM Spreadsheet for 200G/L High Loss C2M



Parameter	Setting	Units	Information			Parameter	Setting	Units
f_b	106.25	GbD		DIAGNOSTICS	0	logical	package_tl_gammm0_a1_a2	[0 0.0008455 0.000340225]
f_min	0.05	GHz		DISPLAY_WINDOW	0	logical	package_tl_tau	0.00644805
Delta_f	0.01	GHz		CSV_REPORT	0	logical	package_Z_c	[92 92 ; 70 70; 80 80; 100 100]
C_d	[0.4e-4 0.9e-4 1.1e-4; 0.4e-4 0.9e-4 1.1e-4]	nF	[TX RX]	RESULT_DIR	\\results\C2M [date]\			
L_s	[0.13 0.15 0.14; 0.13 0.15 0.14]	nH	[TX RX]	SAVE_FIGURES	0	logical		
C_b	[0.3e-4 0.3e-4]	nF	[TX RX]	Port Order	[1 3 2 4]			
z_p select	[1 2]		[test cases to run]	RUNTAG	C2M_RCoS_eval			
z_p (TX)	[15 30; 11; 11; 0.5 0.5]	mm	[test cases]	COM_CONTRIBUTION	0	logical	board_tl_gammm0_a1_a2	[0 6.44084e-4 3.6036e-05]
z_p (NEXT)	[8 8; 0; 0; 0; 0]	mm	[test cases]	Operational			board_tl_tau	5.790e-03
z_p (EXT)	[15 30; 11; 11; 0.5 0.5]	mm	[test cases]	ERL Pass threshold	10	dB	board_Z_c	100
z_p (RX)	[8 8; 0; 0; 0; 0]	mm	[test cases]	COM Pass threshold	3	db	z_bp (TX)	125
PKG_Tx_FF_preset	0			DER_0	1.00E-04		z_bp (NEXT)	0
C_p	[0.5e-4 0.5e-4]	nF	[TX RX]	T_r	3.75E-03	ns	z_bp (EXT)	125
R_0	50	Ohm		FORCE_TR	1	logical	z_bp (RX)	0
R_d	[50 50]	Ohm	[TX RX]	PMO_type	C2C		C_0	[0.2e-4 0]
A_v	0.413	V	vp/vf=	EVI	1		C_1	[0.2e-4 0]
A_fg	0.413	V	vp/vf=	TDR and ERL options		logical	Include PCB	0
A_ng	0.45	V		TDR	1	logical		
L	4			ERL	1	logical	Selection (rectangle, gaussian, dual, vpk, k, triangle)	
M	32			ERL_ONLY	0	ns	Histogram_Window_Weight	0.02
filter and Eq				TR_TDR	0.01		Qr	0.02
f_r	0.75		*fb	N	800	logical		
c(0)	0.54		min	TDR Butterworth	1		KQ parameters	
c(-1)	[-0.34; 0.02; 0]		[minstep; max]	beta_x	0		f_v	0.594
c(-2)	[0.02; 0.12]		[minstep; max]	rho_x	0.618		f_f	0.594
c(-3)	[-0.06; 0.02; 0]		[minstep; max]	TDR_W_TXPKG	0	UI	f_n	0.594
c(-4)	[0.02; 0.06]		[minstep; max]	N_bx	8		f_2	79.688
c(1)	[-0.12; 0.02; 0.1]		[minstep; max]	fixture delay time	[0 0]		A_ft	0.450
N_b	24	UI		Tukez_Window	1		A_nt	0.450
b_max(1)	0.85		As/dfe1	Noise_jitter		UI	Floating Tap Control	
b_max(2..N_b)	[0.5 0.3 0.3 0.2 ones(1,20)]		As/dfe2..N_b	sigma_RJ	0.01	UI	N_bg	6
b_min(1)	0.3		As/dfe1	A_DD	0.02	V^2/GHz	N_bf	3
b_min(2..N_b)	[0.2 0.05 0.05 -0.05 ones(1,20)]		As/dfe2..N_b	eta_0	4.10E-09	dB	N_f	80
g_DC	[-20; 1.0]	dB	[minstep; max]	SNR_TX	33		bmax_s	0.2
f_z	42.5	GHz		R_LM	0.95		max DFE value for float	
f_p1	42.5	GHz		Enforce Causality	1		Receiver testing	
f_p2	106.25	GHz		S-parameter magnitude extrapol	trend_to_DC		RX_CALIBRATION	0
g_DC_HP	[-6; 1.0]		[minstep; max]				Sigma BBN step	5,00E-03
f_HP_PZ	1.328125	GHz						
Butterworth	1	logical	include in fr					
Raised_Cosine	0	logical	include in fr					
RC_Start	6.70E+10	Hz	start freq for RCoS					
RC_end	7.97E+10	Hz	end freq for RCoS					



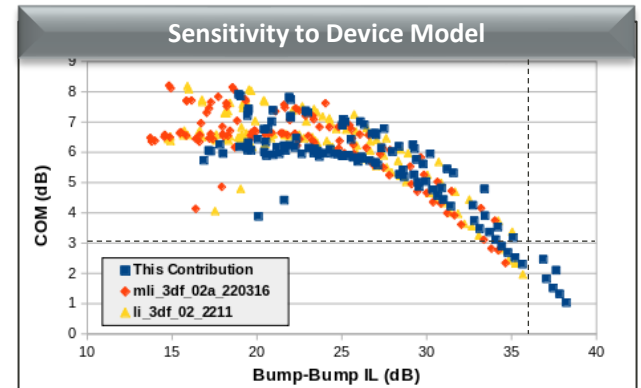
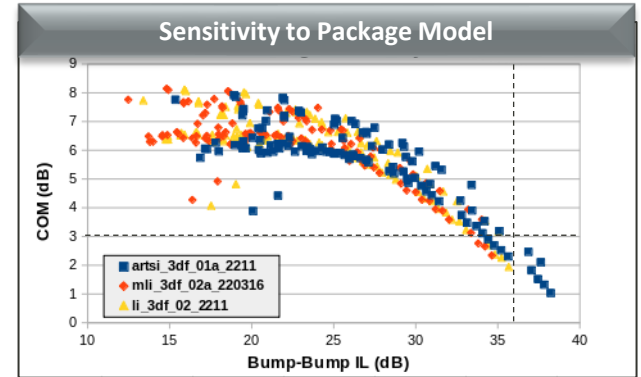
Channel List

CH #	Source	Supporting Presentation	Contributor
36	OSFP MSA	OSFP 200GEL	Amphenol and Keysight
2	rabinovich_3df_022422	rabinovich_3df_01a_220224	Rick Rabinovich, Keysight
21	akinwale_3df_01_2209	akinwale_3df_elec_01_220921	Femi Akinwale, Intel
21	akinwale_3df_02_2209		
21	akinwale_3df_03_2209		
3	rabinovich_3df_01_2209	rabinovich_3df_elec_01b_220921	Rick Rabinovich, Keysight
3	rabinovich_3df_02_2209		
5	tracy_3df_02_2211	tracy_3df_02_2211	Nathan Tracy, TE Connectivity

Sensitivity to Device Model

- Basically, device model makes less significant impact on bump-bump loss budget analysis
- ASIC capability will affect host reach and cause different levels of reflection
 - Further study needed

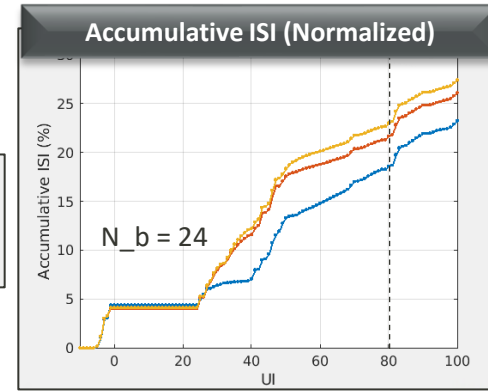
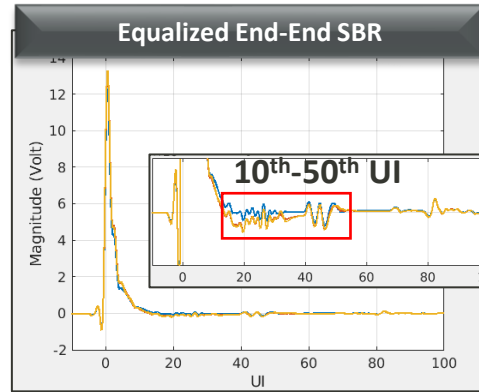
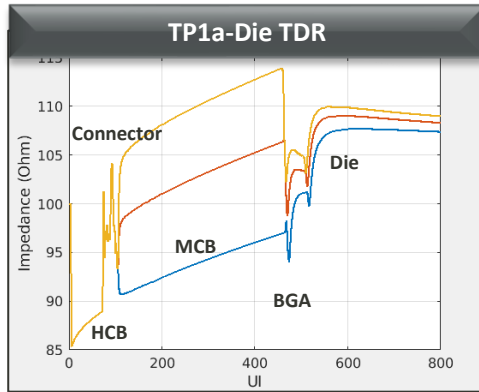
Parameter	This Presentation	mli_3df_02a_220316	li_3df_02_2211
C_d	[0.4e-4 0.9e-4 1.1e-4; 0.4e-4 0.9e-4 1.1e-4]		
L_s	[0.13 0.15 0.14; 0.13 0.15 0.14]		
C_b	[0.3e-4 0.3e-4]		
T_r	3.75E-03	3E-03	3E-03
z_p (TX)	[15 30; 1 1 ; 1 1 ; 0.5 0.5]	[15 30; 1.8 1.8]	[15 30; 2.1 2.1]
z_p (NEXT)	[8 8; 0 0 ; 0 0 ; 0 0]	[8 8; 0 0]	[8 8; 0 0]
z_p (FEXT)	[15 30; 1 1 ; 1 1 ; 0.5 0.5]	[15 30; 1.8 1.8]	[15 30; 2.1 2.1]
z_p (RX)	[8 8; 0 0 ; 0 0 ; 0 0]	[8 8; 0 0]	[8 8; 0 0]
C_p	[0.5e-4 0.5e-4]	[0.4e-4 0.4e-4]	[0.6e-4 0.6e-4]
package_tl_gamma0_a1_a2	[0 0.0008455 0.000340225]	[0 0.00089 0.000155]	[0.0005 0.00089 0.0002]
package_tl_tau	0.00644805	0.006141	0.006141
package_Z_c	[92 92 ; 70 70; 80 80; 100 100]	[92 92 ; 70 70; 80 80; 100 100]	[92 92 ; 70 70; 80 80; 100 100]



UI Span for Floating Tap: N_f



Channel	COM	Bump-Bump IL
85 Ohm	3.48 dB	33.13 dB
93 Ohm	3.74 dB	32.81 dB
100 Ohm	4.25 dB	32.73 dB



— akinwale_3df_01_2209/85ohms/C2M_PCB_85ohms_25dB_202208016_v2
— akinwale_3df_02_2209/93ohms/C2M_PCB_93ohms_25dB_202208016_v2/
— akinwale_3df_03_2209/100ohms/C2M_PCB_100ohms_25dB_202208016_v2/

* Take test case 2 as example
 * 3 representative channels are selected

- Reflections due to inevitable mechanical transitions in channels, especially the transition to connector and package, are mainly located at 10th-50th UI for 30mm package
- Severe reflection region is up to 80th UI → N_f = 80

Thank you

Questions and Discussions